

IEEE Standard Test Procedure for Impulse Voltage Tests on Insulated Conductors

Sponsor

**Insulated Conductors Committee
of the
IEEE Power Engineering Society**

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IEEE Standards Board

Abstract: A test procedure for impulse testing of insulated conductors (cables) and cables with accessories installed (cable systems) is provided. This procedure can be used as a design or qualification test for cables or for cable systems. This test procedure is not intended to replace any existing or future standards covering cable or cable accessories, impulse generators, impulse testing or voltage measurements. It is intended to supplement such standards by indicating specific procedures for a specific type of cable system or cable system component.

Keywords: cable, cable systems, impulse voltage, insulated conductors

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Introduction

(This introduction is not a part of IEEE Std 82-1994, IEEE Standard Test Procedure for Impulse Voltage Tests on Insulated Conductors.)

This revision of IEEE Std 82-1963, Test Procedure for Impulse Voltage Tests on Insulated Conductors, now contains a test procedure for extruded dielectric cables rated 2500 V and above. The impulse voltage test procedures for both laminated and extruded cables and cable systems were also updated to correspond with other standards and specifications.

This standard was prepared by Task Force 12-5 of the Tests and Measurements Subcommittee 12 of the Insulated Conductors Committee of the IEEE Power Engineering Society.

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